

PRECISION BATTERY TESTER BT6065, BT6075

NEW



Introducing the industry's most precise battery tester Ideal for cell grading

0.01 μΩ 5-1/2 digit Max. AC-IR resolution

 $1 \mu V$ 7-1/2 digit Max. DCV resolution

12 ms Max. Ω and V test speed



The precision battery tester BT6075 and BT6065 are designed for OCV/AC-IR testing of high-capacity EV battery cells with low internal resistance. The extremely high resolution enables these models to perform advance cell-grading. These testers powerfully facilitate the creation of reliable and efficient OCV/IR testing systems with their innovative features and capability of high-speed testing.





High-precision grading of high-capacity batteries

Next-gen battery testing





Top-tier battery measurement performance

Highest precision

Choose from 2 models depending on your testing process







Beginning- and end-of-line (BOL, EOL) test

For high-precision cell grading

BT6075

Voltage display: 7-1/2 digits

Max. DCV resolution: 1 µV

Max. AC-IR resolution: $0.01 \mu\Omega$

In-line test of formation and aging process

OCV/AC-IR test for cell screening

BT6065

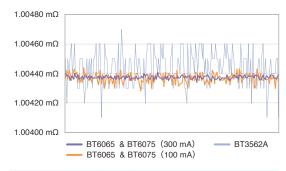
Voltage display: 6-1/2 digits

Max. DCV resolution: 10 μV

Max. AC-IR resolution: 0.01 $\mu\Omega$

Exceptional reproducibility for AC-IR and DCV measurements

Excellent resistance measurement resolution and accuracy

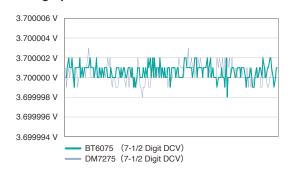




AC-IR offers a 10 nΩ resolution.

At a measurement current of 300 mA, stable measurement data is obtained with an excellent SN ratio suitable for inspecting low-resistance batteries.

Voltage measurement accuracy comparable to a high-precision voltmeter



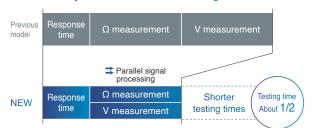
BT6075	±0.0012% rdg. ±11 μV
BT6065	±0.002% rdg. ±20 μV

No additional voltmeter is needed for OCV/IR testing. Both models, one with 7-1/2 digits (resolution of 1 μ V) and the other with 6-1/2 digits (resolution of 10 μ V), feature unparalleled measurement accuracy.

Truly simultaneous Ω/V measurement

Fast testing without sacrificing precision

Simultaneously measure resistance and voltage with 1 instrument



6 sampling time settings

1	Measurement function	FAST1	FAST2	MEDIUM1	MEDIUM2	SLOW1	SLOW2
	OV 50 Hz	4 ma	10 ms	20 ms	40 ms	100 mg	200 ma
	60 Hz	4 ms	10 1115	17 ms	33 ms	100 ms	200 ms

The BT6065 and BT6075 deliver high-speed measurement that goes beyond conventional battery testers. With two A/D converters, the instruments can perform simultaneous resistance and voltage measurement in as little as 12 ms. As a result, they can be used to build systems that deliver both testing efficiency and precision.

"We want to perform testing efficiently with two instruments."

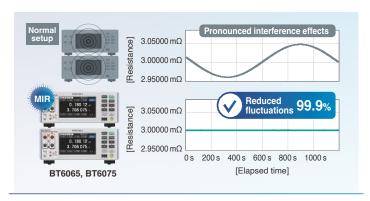


Stable measurement with the MIR mode (mutual interference reduction)

Ordinarily, mutual interference causes measured values to fluctuate when making simultaneous measurements with two battery testers placed in close proximity. The MIR mode reduces mutual interference to ensure stable measurement. The feature makes possible accurate, high-speed parallel-testing with two testers.

Mutual interference reduction (MIR) technology features

- · No need for additional accessories like sync cables
- Unlike an older technology known as pulse output functionality, the MIR mode facilitates reliable parallel testing.



Delivers easy, reliable parallel-testing

"We want to measure numerous channels accurately."

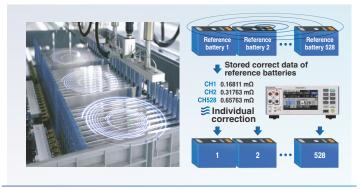


Compensation of individual channels with referential adjustment

When measuring rows of batteries in a tray, eddy currents occurring in the metal enclosures of adjacent batteries cause measurement error. The referential adjustment function, which accurately compensates for the effects of eddy currents by using actual batteries as a reference, allows more accurate measurement.

Referential adjustment features

- · Referential adjustment: up to 528 channels
- Adjustment data for up to six batteries (6 × 528 channels) can be saved on the instrument using its "panel save" feature.



Accurately compensating for the effects of eddy currents caused by adjacent batteries

"We're concerned about abrupt system stoppages."



Significantly improving route resistance tolerance

Route resistance refers to the total value of wiring resistance and probe contact resistance in a given testing system. Since the BT6065/BT6075 has high route resistance tolerance, it provides high durability in the face of probe deterioration and increased relay contact resistance. This prevents abrupt testing system stoppages while improving up-time.

Route resistance tolerance

- 10 Ω : with measurement current of 300 mA (3 m Ω range only)
- 50 Ω : with measurement current of 100 mA or less (all ranges)



Improving the long-term reliability of testing systems

"We want to replace probes less frequently."

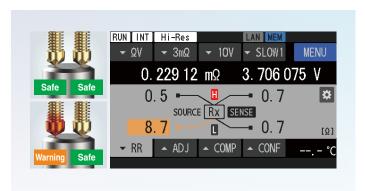


Continuously monitoring for errors with the route resistance monitor

The route resistance monitor displays individual wiring route resistance values for 4-terminal measurement. This feature lets you continuously watch for wiring errors like probe wear and wire breaks. The feature can predict maintenance needs and lower operating costs by helping you make numerically-based decisions as to which probe needs to be replaced.

Route resistance monitor features

- Dual threshold settings (WARNING, FAIL)
- Improved testing reliability by simultaneously measuring route resistance for $\boldsymbol{\Omega}$ and V



Monitoring route resistance and displaying a warning before a measurement error occurs



AC four-terminal method

Resistance measurement, which is performed using the AC 4-terminal method at 1 kHz, is not affected by factors such as wiring resistance.

Averaging measured values

Minimal variability by averaging from 1 to 256 measured values makes measurement stable.

Comparator capability

The instrument's comparator judges resistance and DC voltage values, generating three possible results (Hi, IN, Lo).

Temperature input (temp. sensor terminal)

The optional Temperature Sensor Z2005 can be used to measure ambient temperature.

Saving measurement conditions

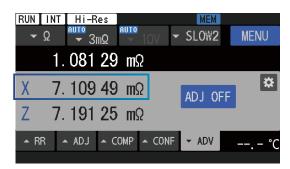
Save and load up to six sets of measurement conditions, including referential adjustment values.

Self-calibration (resistance and DC voltage)

Maintain high precision by correcting for gain fluctuations and minuscule drift in internal measurement circuitry.

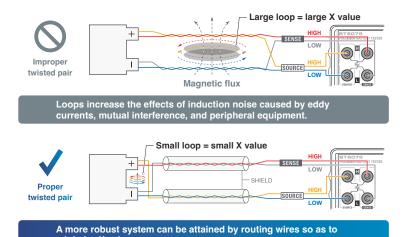
Seamless system integration

Boosting testing systems' durability



Function for displaying the wiring's reactance X and impedance Z

The instruments provide an advanced mode that can display reactance X and impedance Z. This capability is useful when trouble-shooting issues at system startup and when optimizing wiring layouts.





Command compatibility mode

Communication commands from the previous BT3562A model can be used without modification. As a result, you can replace just the battery testers and verify proper operation of newly installed equipment right away.

✓ MENU > EXT I/O > EXT I/O TEST ✓ OUTPUT							
INDEX	EOM	E	RR	RRPA	SS	RRWARN	RRFAIL
RHI	RIN	R	LO	۷ŀ	11	VIN	V LO
PASS1	PASS2	FAIL1		FAI	L2		
INPUT							
TRIG	OAD.	J CAI		LIB	CA	ALIB2	KLOCK
LOADO	LOAD	1	LO	AD2			

minimize X values.

Ext. I/O monitor

In addition to checking EXT. I/O input signals on the screen, you can turn output signals on and off as desired. This capability also simplifies verification of PLC programming.

< MENU >	I/F > CMD MONITOR	\square \times
	nicate:BT3562A ON	. A
*TRG:: MEAS? 0.16593E-3.	3. 296137E+0	
*TRG::MEAS?	3. 2901372+0	
0.16598E-3,	3. 296138E+0	
*TRG::MEAS?		
0.16594E-3, *TRG::MFAS?	3. 296137E+0	
0. 16601E-3,	3. 296138E+0	
*TRG::MEAS?	0.2001002	V

Commands monitor

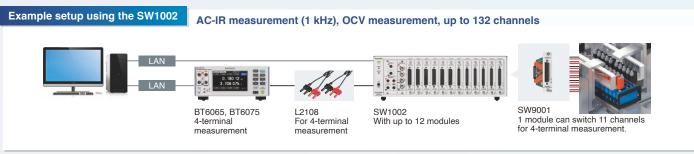
Display communications data (received commands and sent data) on the screen. This capability is useful when checking PLC programming.

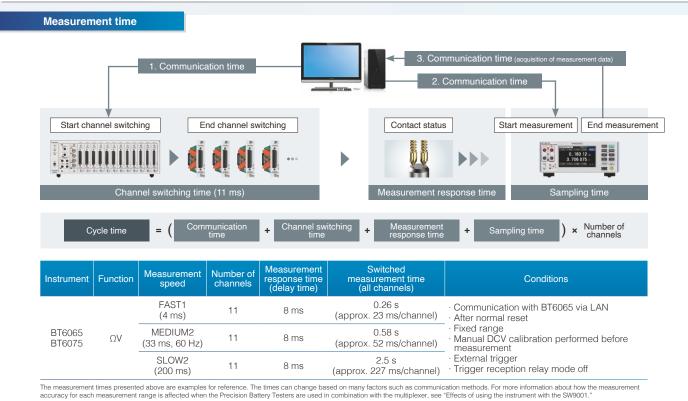
Options

Dedicated multiplexer optimized for high-speed, high-precision measurement

Hioki's multiplexer can also be zero-adjusted, resulting in a more accurate system that corrects the effects of eddy currents.







Multiplexer specifications

Switch Mainframe SW1001, SW1002

Number of slots	3 slots (SW1001) 12 slots (SW1002)			
Supported BT6065/ BT6075 module	Multiplexer Module SW9001 (2-wire, 4-wire)			
Max. input voltage	DC 60 V, AC 30 V rms, 42.4 V peak			
Interfaces	LAB, USB, RS-232C (host), RS-232C (command transfer function)			
EXT. I/O	SCAN input, SCAN_RESET input, CLOSE output (scan control)			

Multiplexer Module SW9001

Wiring method	2-wire or 4-wire		
Number of channels	22 channels (2-wire method) or 11 channels (4-wire method)		
Contact method	Mechanical relay		
Channel switching time	11 ms (not including measurement time)		
Max. allowable voltage	DC 60 V, AC 30 V rms, 42.4 V peak		
Max. allowable current	DC 1 A, AC 1 A rms		
Connectors used	D-sub 50-pin pin header		

Effects of using the instrument with the SW9001¹¹

Range	Effect
R 3 mΩ (300 mA)	0.1% f.s.
R 3 mΩ (100 mA)	0.1% f.s.
R 30 mΩ	0.03% f.s.
R 300 mΩ	0.03% f.s.
R3Ω	0.03% f.s.
R 30 Ω	0.03% f.s.
All V ranges	5 μV

³⁰ Ω range: source contact check operation not available

Appearance







SW1001 SW1002

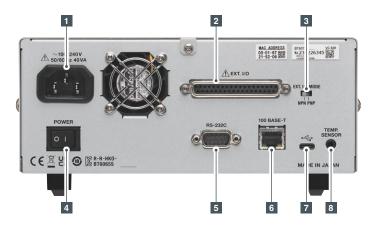
SW9001

^{*1.} Effect before zero adjustment

Interfaces

EXT. I/O RS-232C LAN

- 1 Power inlet
- 2 Ext. I/O connector
- 3 Ext. I/O mode switch
- 4 Power switch
- 5 RS-232C connector
- 6 LAN connector
- 7 Type-C USB connector
- 8 Temp. sensor terminal



Specifications

General specifications

Accuracy guaranteed: 1 year

Operating temperature and humidity range	0°C to 40°C (32°F to 104°F), 80% RH or less (non-condensing)
Standard compliance	Safety: EN 61010 EMC: EN 61326 Class A
Power supply	Rated supply voltage: 100 V to 240 V AC (assuming voltage fluctuations of \pm 10% of the rated supply voltage) Rated power supply frequency: 50 Hz, 60 Hz Maximum rated power: 40 VA
Interfaces	LAN (10BASE-T/100BASE-T, TCP/IP) USB (COM mode, C-type receptacle) USB (MEM mode* ¹ , A-type receptacle, for Z4006 USB Drive) RS-232C (9600 bps, 19200 bps, 38400 bps) EXT. I/O
Dimensions and weight	Approx. 215W \times 88H \times 313D mm (8.5W \times 3.5H \times 12.3D in.) (excluding protruding parts) Approx. 3.1 kg (6.8 lb.)
Included accessories	Power cord × 1, Startup Guide × 1, Operating Precautions × 1

^{*1.} Only screenshots can be saved.

ania annoifications

Basic specifications									
Measurement range		Resistance ranges: 3 m Ω , 30 m Ω , 300 m Ω , 3 Ω , 30 Ω Voltage ranges: 10 V, 100 V							
Measurement functions	ΩV,	ΩV, Ω, V							
	Mea	suremen	t functions	10 ΜΩ)	HI	HIGH Z		
DC input resistance	ΩV	/Ω		_	±10%	1	1 GΩ or greater		
(10 V range)	V				±10%		10 GΩ or greater		
	(Fixe	ed at 10) MΩ set	ting whe	en using	the 100	V range)	
Max. input voltage	DC :	±120 V							
Max. rated line-to-ground voltage	DC	±120 V							
	Meas	surement ion	FAST1	FAST2	MEDIUM1 (MED1)	MEDIUM2 (MED2)	SLOW1	SLOW2	
	ΩV	50 Hz 60 Hz	4 ms	10 ms	20 ms 17 ms	40 ms 33 ms	100 ms	200 ms	
Sampling time	Ω	50 Hz 60 Hz	4 ms	10 ms	20 ms 17 ms	40 ms 33 ms	100 ms	200 ms	
	V	50 Hz 60 Hz	4 ms	10 ms	20 ms 17 ms	40 ms 33 ms	100 ms	200 ms	
	Temperature measurement: approx. 2 s								
Time added for MIR resistance measurement		resista s to 12 i		asureme	ent MIR n	node er	abled:		
Response time		rox. 8 n en measi		resistan	ce and vo	oltage of	a 4 V batt	tery)	
Accuracy guarantee conditions	Accuracy guaranteed temperature and humidity range: 23°C ±5°C (73°F ±9°F), 80% RH or less Warm-up time: 60 min. or more Resistance self-calibration: performed after warm-up time DC voltage self-calibration: performed after warm-up time Adjustment processing • Resistance measurement: after zero adjustment or after referential adjustment is enabled • DC voltage measurement: after zero adjustment								
Functions	calik (528 resis com HiTe								

command monitor, EXT. I/O test

Resistance measurement accuracy

		Range (measurement current)*1						
SLOW2		3 mΩ (300 mA)	3 mΩ (100 mA)	$\begin{array}{c} 30 \text{ m}\Omega \\ \text{(100 mA)} \end{array}$	300 mΩ (10 mA)	3 Ω (1 mA)	30 Ω (100 μA)	
(sampling spe	eu)		±0.08	% rdg.		±0.10% rdg.	±0.15% rdg.	
HIGH RESOLUTION	OFF	±0.1 μΩ	±0.5 μΩ	±1 μΩ	±10 μΩ	±100 μΩ	±1 mΩ	
THATTLESOLUTION	ON	±0.08 μΩ	±0.50 μΩ	±0.5 μΩ	±5 μΩ	±50 μΩ	±0.5 mΩ	
Max. display value								
HIGH RESOLUTION	OFF	5.1000 mΩ	5.1000 mΩ	51.000 mΩ	510.00 mΩ	5.1000 Ω	51.000 Ω	
HIGH RESOLUTION	ON	5.10000 mΩ	5.10000 mΩ	51.0000 mΩ	510.000 mΩ	5.10000 Ω	51.0000 Ω	
Resolution								
HIGH RESOLUTION	OFF	0.1 μΩ	0.1 μΩ	1 μΩ	10 μΩ	100 μΩ	1 mΩ	
HIGH RESOLUTION	ON	0.01 μΩ	0.01 μΩ	0.1 μΩ	1 μΩ	10 μΩ	100 μΩ	
Measurement current freque	ncy			1 kHz =	±0.2 Hz			

*1. Rms value, measurement current error within ±10%
Additional accuracy deterioration
Temperature coefficient: add the following value to the measurement accuracy if the temperature is
0°C to 18°C or 28°C to 40°C: (measurement accuracy x 0.1) / °C
Addition when resistance measurement MIR mode is enabled: add ±0.01% rdg. to the resistance measurement accuracy.

DC voltage measurement accuracy BT6065

	Range							
SLOW2 (sampling speed)	10 V	100 V						
	±0.002% rdg. ±20 μV	±0.004% rdg. ±0.6 mV						
Max. display value	±12.00000 V	±120.0000 V						
Resolution	10 μV	100 μV						

BT6075

	Range							
SLOW2	10 V	100 V						
(sampling speed)	±0.0012% rdg. ±11 μV	±0.003% rdg. ±0.60 mV						
Max. display value	±12.000000 V	±120.00000 V						
Resolution	1 μV	10 μV						

Additional accuracy deterioration

Temperature coefficient: add the following value to the measurement accuracy if the temperature is 0°C to 18°C or 28°C to 40°C: (measurement accuracy × 0.1) / °C

Temperature measurement accuracy

Range	-10.0°C to 60.0°C (14°F to 140°F)
	±0.5°C (measurement temperature of 10.0°C to 40.0°C) ±1.0°C (measurement temperature of -10.0°C to 9.9°C, 40.1°C to 60.0°C)

Route resistance measurement accuracy

Resistance range	3 mΩ		30 mΩ	300 mΩ	3 Ω	30 Ω	
Measurement current	300 mA	100 mA	100 mA	10 mA	1 mA	100 μΑ	
Accuracy	3.0% rdg. $\pm 0.5~\Omega$ (3 m Ω , 30 m Ω , 300 m Ω , or 3 Ω resistance range) 3.0% rdg. $\pm 3~\Omega$ (30 Ω resistance range)						
Max. display value	10.0 Ω	50.0 Ω	50.0 Ω	50.0 Ω	50.0 Ω	500 Ω	
Route resistance resolution	0.1 Ω	0.1 Ω	0.1 Ω	0.1 Ω	0.1 Ω	1 Ω	

Options

Test leads



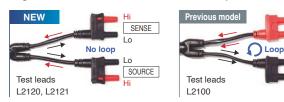


PIN TYPE LEAD L2100 Rated voltage: 1000 V DC Rated current: 2 A DC Approx. length: L: 1.4 m (4.6 ft.) A: 300 mm (11.8 in.) B: 172 mm (6.8 in.)



Test leads featuring a new design that minimizes the effects of eddy currents

Internal twisted-pair wiring right up to the tip of the test lead minimizes magnetic noise and reduces measurement variability.



Conventional test leads may also be used

Conventional test leads may also be used by changing the orientation in which the test leads are connected. Making measurements with the test leads connected improperly will not damage the instrument.





SENSE

Hi SOURCE

SOURCE

Lo

SENSE

When using L2120, L2121

When using L2100

PC connectivity



RS-232C CABLE L9637

9-pin/9-pin, 3 m (9.8 ft.)



USB CABLE L9510 USB A-C type

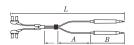


USB DRIVE Z4006 16 GB



LAN CABLE 9642

Straight Ethernet cable, supplied with straight-to-cross conversion adapter, 5 m (16.4 ft.)



Lead length
L: overall length
A: from junction to probe
B: probe length

Other



TEMPERATURE SENSOR Z2005

1 m (3.3 ft.)



0 ADJ BOARD Z5038

For L2120, L2100



TIP PIN 9772-90

To replace the tip on the pin-type lead L2120/ L2100 (one pin)

Using multiplexers



SWITCH MAINFRAME SW1002

12 slots, max. 132 channels (4-wire)



SWITCH MAINFRAME SW1001

3 slots, max. 33 channels (4-wire)



MULTIPLEXER MODULE SW9001

Max. 11 channels (4-wire), 2-wire/4-wire

DISTRIBUTED BY



CONNECTION CABLE L2108

4-terminal banana, 0.84 m (2.8 ft.)

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81 Koizumi, Ueda, Nagano 386-1192 Japan https://www.hioki.com/



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